

## Call for Papers

# 1st International Workshop on Software Patterns and Quality

(SPAQu'07) in Nagoya, Japan, December 3, 2007

collocated with 14th Asia-Pacific Software Engineering Conference (APSEC'07)

<http://patterns-wg.fuka.info.waseda.ac.jp/SPAQU/>

### Workshop Committee

#### Organizers:

Hironori Washizaki, National Institute of Informatics, Japan

Nobukazu Yoshioka, National Institute of Informatics, Japan

#### Program Committee (TBD):

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Yann-Gael Gueheneuc, University of Montreal, Canada

Yasuyuki Hirose, Ryukyuu University, Japan

Yasuyuki Tahara, National Institute of Informatics, Japan

### Publication

Accepted papers of the workshop will be published in the workshop proceedings with an International Standard Book Number (ISBN) by the Information Processing Society of Japan. Selected papers will be considered for publication in issues of some international journals (TBD).

### Sponsors and Contact Us

The workshop is co-sponsored by IPSJ/SIGSE Patterns WG and SSE Project of National Institute of Informatics. Contact: [washizaki@nii.ac.jp](mailto:washizaki@nii.ac.jp)

### Objective and Motivation

A software pattern is an abstracted repeatable solution to a commonly occurring problem under a certain context with forces in software development. Patterns help people involved in software to share experience-based proven solutions and develop products, manage processes, projects and organizations, and communicate each other more efficiently and effectively. Although numbers of pattern catalogues have been published, little known about how to specify, measure and evaluate quality of those patterns and/or their application results. This workshop seeks to gain an improved understanding on the theoretical, social, technological and practical issues related to quality aspects of patterns including security and safety aspects.

Suggested topic areas of interest include, but are not limited to:

- Quality by software patterns: management, assurance, measurement, rating, testing, review and evaluation of quality in software products, processes, people and projects with software patterns (e.g. how much does maintainability become high by design patterns?)
- Quality of software patterns: management, assurance, measurement, rating, testing, review and evaluation of quality of software patterns
- Quality specific patterns: e.g., security patterns and safety patterns
- Quality aspects of activities related to software patterns
- Quality with pattern system and languages: how to build quality systems of patterns, pattern compositions, and stable/testable pattern languages
- Patterns and pattern languages pitfalls and how to avoid them
- Nature of "Quality Without A Name" (QWAN) in software development
- Methods and tools: modeling tools, measurement tools, testing tools and management tools related to software patterns quality
- Case studies and lessons learned from the viewpoint of quality
- Relationships among software patterns and related technologies from the viewpoint of quality

### Paper Submission

The workshop invites the submission of both full papers and short papers. Full papers shall describe in detail research projects and experience, and must not exceed 6 pages in the IEEE conference format ([http://www.computer.org/portal/pages/cscps/cps/cps\\_forms.html](http://www.computer.org/portal/pages/cscps/cps/cps_forms.html)).

Short papers shall describe visions, new perspectives, research experience, or emerging research questions, and must not exceed 2 pages of the same format. Both types of submissions will be reviewed by the program committee for their relevance as well theoretical, technological and practical contributions to the workshop topics. We especially encourage the submission of provoking or unconventional ideas that can lead to lively and productive discussions. Please send your submission (in PDF) to [washizaki@nii.ac.jp](mailto:washizaki@nii.ac.jp) by September 14, 2007.

### Important Dates (TBD)

Full and short paper submission	September 14, 2007
Acceptance notification	October 15, 2007
Final camera-ready	November 2, 2007
Workshop	December 3, 2007